

**Issue Classification**

Application/Control No.

09965030

Applicant(s)/Patent Under Reexamination

NIWA ET AL.

Examiner

Shin, Kyung H

Art Unit

2143

**ORIGINAL**

CLASS

SUBCLASS

709

238

**INTERNATIONAL CLASSIFICATION**

CLAIMED

NON-CLAIMED

G 0 6 F 15 / 173 (2006.01.01)

**CROSS REFERENCE(S)**

CLASS

SUBCLASS (ONE SUBCLASS PER BLOCK)

709

249

230

710

305

306

370

392

463

466

Shin, Kyung H

8/17/2007

(Assistant Examiner)

(Date)

Total Claims Allowed:

6

  
(Legal Instruments  
Examiner)

08/28/07

(Date)

  
DAVID WILEY  
SUPERVISORY PATENT EXAMINER  
TECHNOLOGY CENTER 2100  
(Primary Examiner) (Date)

O.G. Print Claim(s)

1

O.G. Print Figure

Fig. 22